

R1LV3216R Series

32Mb Advanced LPSRAM (2M word x 16bit / 4M word x 8bit)

REJ03C0367-0001 Preliminary Rev.0.01 2008.03.24

Description

The R1LV3216R Series is a family of low voltage 32-Mbit static RAMs organized as 2,097,152-word by 16-bit, fabricated by Renesas's high-performance 0.15um CMOS and TFT technologies.

The R1LV3216R Series is suitable for memory applications where a simple interfacing, battery operating and battery backup are the important design objectives.

The R1LV3216R Series is provided in 48-pin thin small outline package [TSOP (I): 12mm x 20mm with pin pitch of 0.5mm] and 52-pin micro thin small outline package [μ TSOP (II): 10.79mm x 10.49mm with pin pitch of 0.4mm]. It gives the best solution for compaction of mounting area as well as flexibility of wiring pattern of printed circuit boards.

Features

- Single 2.7~3.6V power supply
- Small stand-by current: 4 µA (3.0V, typical)
- No clocks, No refresh
- All inputs and outputs are TTL compatible.
- Easy memory expansion by CS1#, CS2, LB# and UB#
- Common Data I/O
- Three-state outputs: OR-tie Capability
- OE# prevents data contention on the I/O bus

Ordering Information

Type No.	Access time	Package
R1LV3216RSA-5S%	55 ns ^{*1}	12mm x 20mm 48-pin plastic TSOP (I)
R1LV3216RSA-7S%	70 ns	(normal-bend type) (48P3R)
R1LV3216RSD-5S%	55 ns ^{*1}	350 mil 52-pin plastic μ-TSOP (II)
R1LV3216RSD-7S%	70 ns	(normal-bend type) (52PTG)

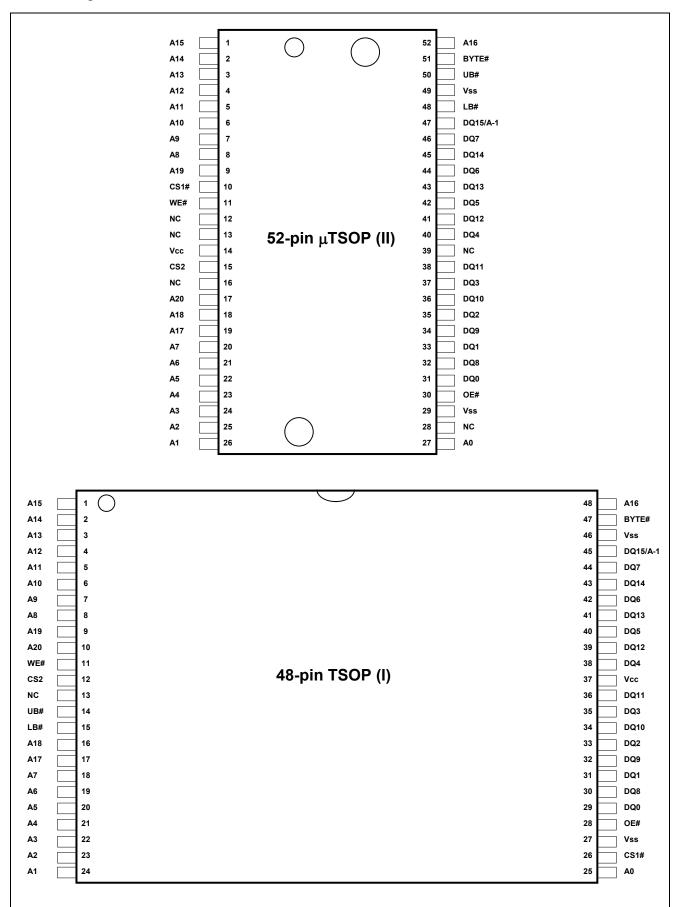
Note1. 55ns parts can be supported under the condition of the input timing limitation toward SRAM on customer's system. Please contact our sales office in your region, in case of the inquiry for 55ns parts.

% - Temperature version: see table below

%	Temperature Range
R	0 ~ +70 °C
I	-40 ~ +85 °C



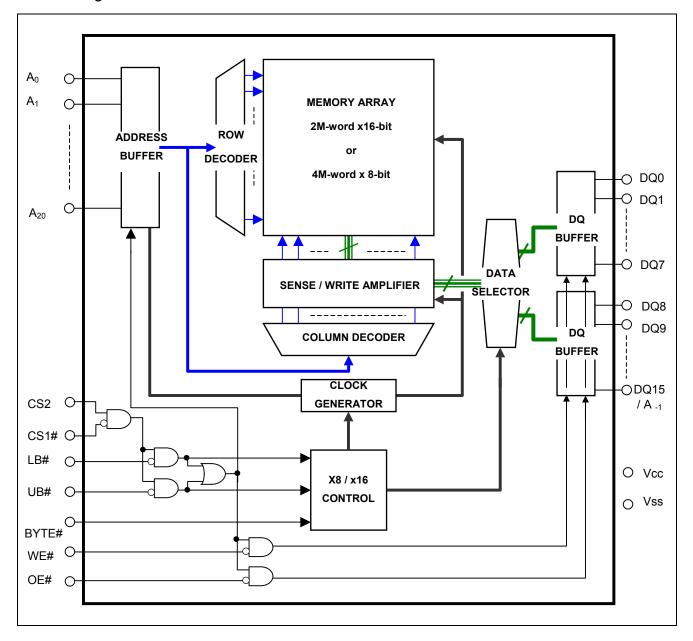
Pin Arrangement



Pin Description

Pin name	Function
Vcc	Power supply
Vss	Ground
A0 to A20	Address input (word mode)
A-1 to A20	Address input (byte mode)
DQ0 to DQ15	Data input/output
CS1#	Chip select 1
CS2	Chip select 2
WE#	Write enable
OE#	Output enable
LB#	Lower byte enable
UB#	Upper byte enable
BYTE#	Byte control mode enable
NC	Non connection

Block Diagram



Operation Table

CS1#	CS2	BYTE#	LB#	UB#	WE#	OE#	DQ0~7	DQ8~14	DQ15	Operation
Н	Х	Х	X	Х	Х	Х	High-Z	High-Z	High-Z	Stand-by
Х	L	Х	X	Х	Х	Х	High-Z	High-Z	High-Z	Stand-by
Х	Х	Н	Н	Н	Х	Х	High-Z	High-Z	High-Z	Stand-by
L	Н	Н	L	Η	L	X	Din	High-Z	High-Z	Write in lower byte
L	Н	Н	L	Η	Н	L	Dout	High-Z	High-Z	Read in lower byte
L	Н	Н	Н	L	L	Х	High-Z	Din	Din	Write in upper byte
L	Н	Н	Н	L	Н	L	High-Z	Dout	Dout	Read in upper byte
L	Н	Н	L	L	L	X	Din	Din	Din	Word write
L	Н	Н	L	L	Н	L	Dout	Dout	Dout	Word read
L	Н	Н	L	L	Н	Н	High-Z	High-Z	High-Z	Output disable
L	Н	Ĺ	Ĺ	L	L	Х	Din	High-Z	A-1	Byte write
L	Н	Ĺ	Ĺ	L	Н	Ĺ	Dout	High-Z	A-1	Byte read
L	Н	Ĺ	L	L	Н	Н	High-Z	High-Z	A-1	Output disable

Note 1. H: V_{IH} L: V_{IL} X: V_{IH} or V_{IL}

Absolute Maximum Ratings

Parameter	Symbol		unit				
Power supply voltage relative to Vss	Vcc		-0.5 to +4.6			-0.5 to +4.6	
Terminal voltage on any pin relative to Vss	V _T		-0.5 ^{*1} to Vcc+0.3 ^{*2}			-0.5 ^{*1} to Vcc+0.3 ^{*2}	
Power dissipation	P_T		W				
Operation temperature	Topr*3	R ver.	0 to +70	°C			
Operation temperature	ТОРГ	I ver.	-40 to +85	°C			
Storage temperature range	Tstg		-65 to 150	°C			
Storage temperature range under high	Tbias*3	R ver.	0 to +70	°C			
Storage temperature range under bias	ibias	I ver.	-40 to +85	°C			

Note 1. –2.0V in case of AC (Pulse width ≤30ns)

- 2. Maximum voltage is +4.6V.
- 3. Ambient temperature range depends on R/I-version. Please see table on page 1.

^{2.} When apply BYTE# ="L", please assign LB#=UB#="L".

Recommended Operating Conditions

Parameter		Symbol	Min.	Тур.	Max.	Unit	Note
Supply voltage		Vcc	2.7	3.0	3.6	V	
		Vss	0	0	0	>	
Input high voltage		V_{IH}	2.4	-	Vcc+0.2	V	
Input low voltage		V_{IL}	-0.2	-	0.4	V	1
Ambient temperature range	R ver.		0	-	+70	°C	2
Ambient temperature range	I ver.	ıa	-40	-	+85	°C	2

Note 1. -2.0V in case of AC (Pulse width ≤ 30 ns)

DC Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions		
Input leakage current	I _{LI}	-	-	1	μΑ	Vin = Vss to Vcc		
Output leakage current	I _{LO}	-	-	1	μΑ	BYTE# \geq Vcc -0.2V or BYTE# \leq 0.2V CS1# =V _{IH} or CS2 =V _{IL} or OE# =V _{IH} or WE# =V _{IL} or LB# = UB# =V _{IH} , VI/O =Vss to Vcc		
Average operating current	Icc1	ı	40 ^{*1}	55	mA	Min. cycle, duty =100%, II/O = 0mA BYTE# \geq Vcc -0.2V or BYTE# \leq 0.2V CS1# =V _{IL} , CS2 =V _{IH} , Others = V _{IH} /V _{IL}		
	I _{CC2}	-	3 ^{*1}	8	mA	Cycle =1 μ s, duty =100%, II/O = 0mA BYTE# \geq Vcc -0.2V or BYTE# \leq 0.2V CS1# \leq 0.2V, CS2 \geq V _{CC} -0.2V, V _{IH} \geq V _{CC} -0.2V, V _{IL} \leq 0.2V		
Standby current	I _{SB}	-	0.1*1	0.3	mA	BYTE# ≥ Vcc -0.2V or BYTE# ≤ 0.2V CS2 =V _{IH}		
Standby current		-	4*1	12	μΑ	~+25°C		
	I _{SB1}	-	7*2	24	μА	8YTE# ≤ 0.2V (1) 0V ≤ CS2 ≤ 0.2V or (2) CS1# ≥ V _{CC} -0.2V,		
	iSB1	-	-	50	μΑ	$\sim +70^{\circ}\text{C}$ (2) CS1# = VCC-0.2V, $CS2 \ge V_{CC}$ -0.2V or (3) LB# = UB# $\ge V_{CC}$ -0.2V,		
		ı	-	80	μΑ	~+85°C		
Output high voltage	V _{OH}	2.4	-	-	٧	BYTE# \geq Vcc -0.2V or BYTE# \leq 0.2V I_{OH} = -0.5mA		
Output low voltage	V _{OL}	-	-	0.4	V	BYTE# ≥ Vcc -0.2V or BYTE# ≤ 0.2V I _{OL} = 2mA		

Note 1. Typical parameter indicates the value for the center of distribution at 3.0V (Ta= 25°C), and not 100% tested.

^{2.} Ambient temperature range depends on R/I-version. Please see table on page 1.

^{2.} Typical parameter indicates the value for the center of distribution at 3.0V (Ta= 40° C), and not 100% tested.

Capacitance

(Ta = 25° C, f =1MHz)

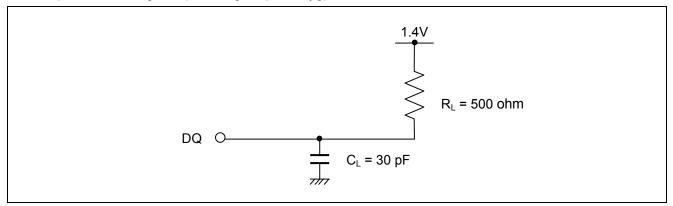
Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Input capacitance	C in	-	-	10	pF	Vin =0V	1
Input / output capacitance	C _{1/O}	-	-	10	pF	V _{I/O} =0V	1

Note1. This parameter is sampled and not 100% tested.

AC Characteristics

Test Conditions (Vcc = $2.7V \sim 3.6V$, Ta = $0 \sim +70^{\circ}C / -40 \sim +85^{\circ}C^{*1}$)

- Input pulse levels: $V_{IL} = 0.4V$, $V_{IH} = 2.4V$
- Input rise and fall time: 5ns
- Input and output timing reference level: 1.4V
- Output load: See figures (Including scope and jig)



Note1. Ambient temperature range depends on R/I-version. Please see table on page 1.

Read Cycle

Parameter	Symbol	Symbol R1LV3216R** (Note 0)		R1LV32	16R**-7S	Unit	Note
		Min.	Max.	Min.	Max.		
Read cycle time	t _{RC}	55	-	70	-	ns	
Address access time	t _{AA}	-	70	-	70	ns	
Chip select access time	t _{ACS1}	-	55	-	70	ns	
Chip select access time	t _{ACS2}	-	55	-	70	ns	
Output enable to output valid	t _{OE}	-	25	-	35	ns	
Output hold from address change	t _{OH}	10	-	10	-	ns	
LB#, UB# access time	t _{BA}	-	55	-	70	ns	
Chin coloct to output in low 7	t _{CLZ1}	10	-	10	-	ns	2,3
Chip select to output in low-Z	t _{CLZ2}	10	-	10	-	ns	2,3
LB#, UB# enable to low-Z	t _{BLZ}	5	-	5	-	ns	2,3
Output enable to output in low-Z	t _{OLZ}	5	-	5	-	ns	2,3
Chin deceler to output in high 7	t _{CHZ1}	0	20	0	25	ns	1,2,3
Chip deselect to output in high-Z	t _{CHZ2}	0	20	0	25	ns	1,2,3
LB#, UB# disable to high-Z	t _{BHZ}	0	20	0	25	ns	1,2,3
Output disable to output in high-Z	t _{OHZ}	0	20	0	25	ns	1,2,3

Write Cycle

Parameter	Symbol	_	16R**-5S te 0)	R1LV32	16R**-7S	Unit	Note
		Min.	Max.	Min.	Max.		
Write cycle time	t _{WC}	55	-	70	-	ns	
Address valid to end of write	t _{AW}	50	-	65	-	ns	
Chip select to end of write	t _{CW}	50	-	65	-	ns	5
Write pulse width	t _{WP}	40	-	55	-	ns	4
LB#, UB# valid to end of write	t _{BW}	50	-	65	-	ns	
Address setup time	t _{AS}	0	-	0	-	ns	6
Write recovery time	t _{WR}	0	-	0	-	ns	7
Data to write time overlap	t _{DW}	25	-	35	-	ns	
Data hold from write time	t _{DH}	0	-	0	-	ns	
Output enable from end of write	t _{OW}	5	-	5	-	ns	2
Output disable to output in high-Z	t _{OHZ}	0	20	0	25	ns	1,2
Write to output in high-Z	t _{WHZ}	0	20	0	25	ns	1,2

Note0. 55ns parts can be supported under the condition of the input timing limitation toward SRAM on customer's system. Please contact our sales office in your region, in case of the inquiry for 55ns parts. In case of t_{AA} =70ns, t_{RC} =70ns.

- 1. t_{CHZ} , t_{OHZ} , t_{WHZ} and t_{BHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.
- 2. This parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition, t_{HZ} max is less than t_{LZ} min both for a given device and from device to device.
- 4. A write occurs during the overlap of a low CS1#, a high CS2, a low WE# and a low LB# or a low UB#. A write begins at the latest transition among CS1# going low, CS2 going high, WE# going low and LB# going low or UB# going low.

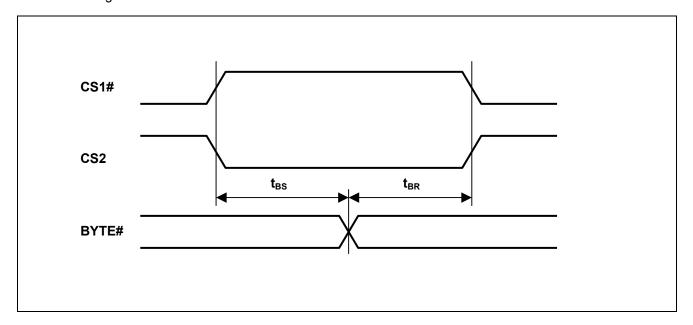
A write ends at the earliest transition among CS1# going high, CS2 going low, WE# going high and LB# going high or UB# going high. t_{WP} is measured from the beginning of write to the end of write.

- 5. t_{CW} is measured from the later of CS1# going low or CS2 going high to end of write.
- 6. t_{AS} is measured the address valid to the beginning of write.
- 7. t_{WR} is measured from the earliest of CS1# or WE# going high or CS2 going low to the end of write cycle.

BYTE# Timing Conditions

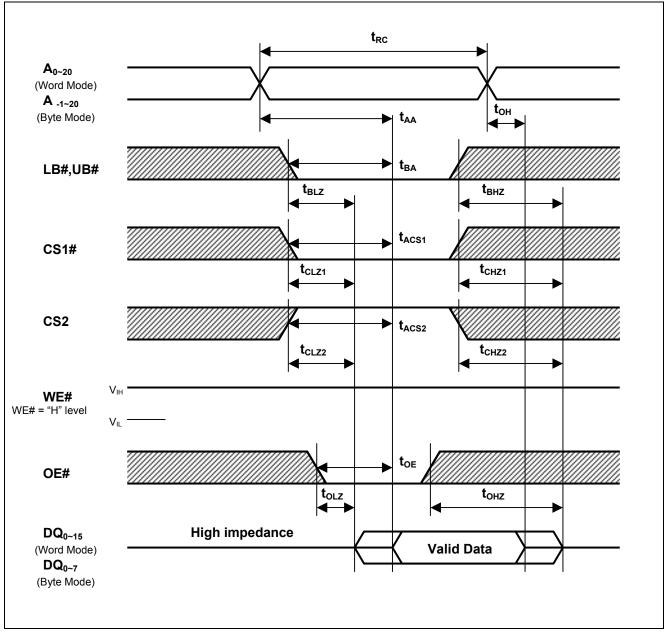
Parameter	Symbol	R1LV32	16R**-5S	R1LV32	16R**-7S	Unit	Note
i didiletei	Symbol	Min.	Max.	Min.	Max.	Offic	
Byte setup time	t _{BS}	5	-	5	1	ms	
Byte recovery time	t _{BR}	5	-	5	-	ms	

BYTE# Timing Waveforms



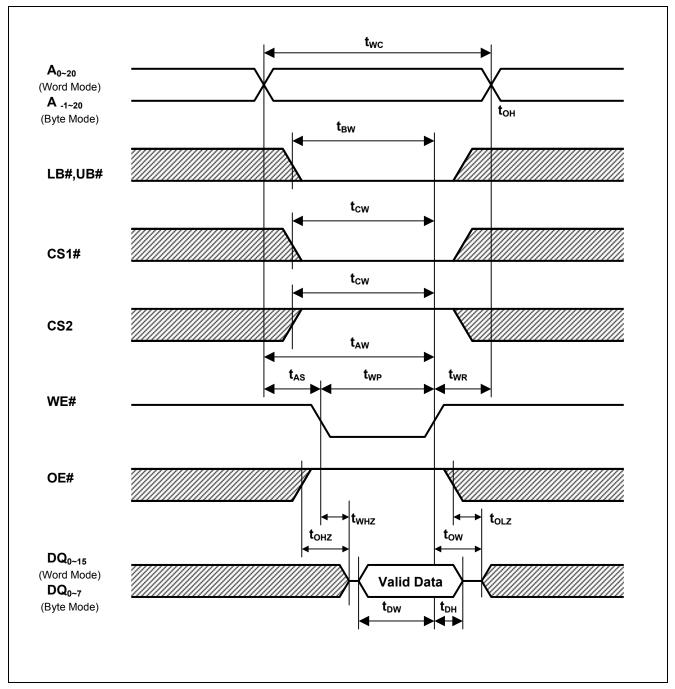
Timing Waveforms

Read Cycle*1



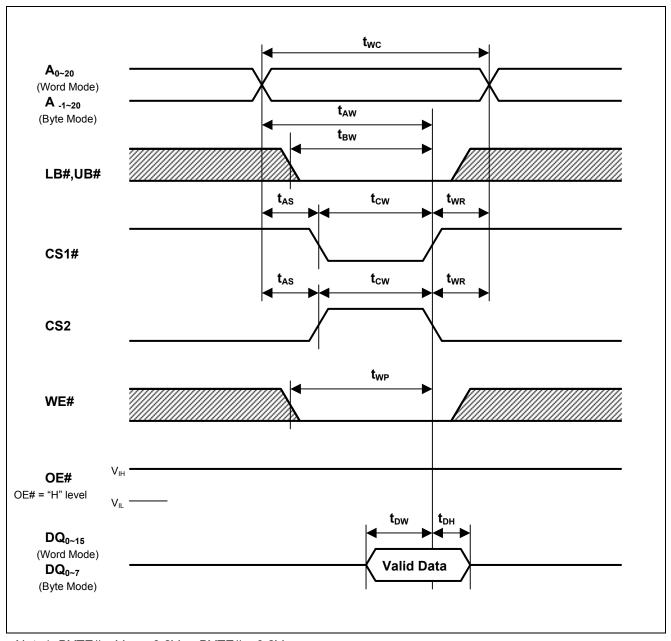
Note1. BYTE# ≥ Vcc – 0.2V or BYTE# ≤ 0.2V

Write Cycle (1)*1 (WE# CLOCK)



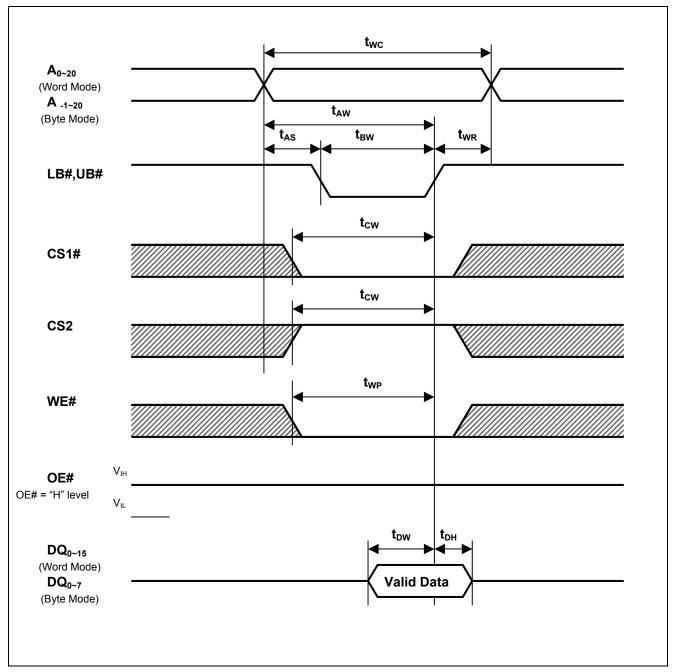
Note1. BYTE# ≥ Vcc – 0.2V or BYTE# ≤ 0.2V

Write Cycle (2)*1 (CS1#, CS2 CLOCK)



Note1. BYTE# ≥ Vcc – 0.2V or BYTE# ≤ 0.2V

Write Cycle (3)*1 (LB#, UB# CLOCK)



Note1. BYTE# ≥ Vcc – 0.2V or BYTE# ≤ 0.2V

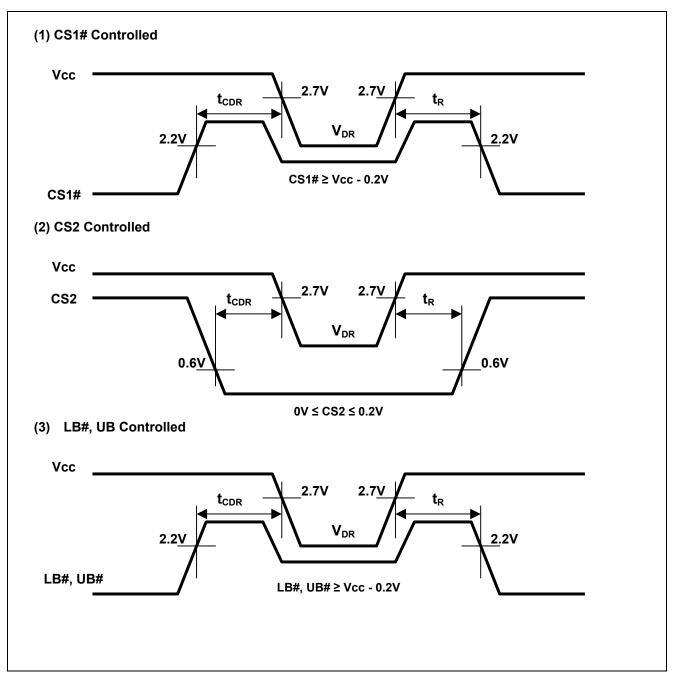
Low Vcc Data Retention Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions ^{*3}		
V _{CC} for data retention	V_{DR}	2.0	-	3.6	V	(1) 0V ≤ 0 (2) CS1# CS2 ≥ (3) LB# = CS1# ≤	Vcc -0.2V or BYTE# ≤ 0.2V CS2 ≤ 0.2V or ≥ V_{CC} -0.2V, V_{CC} -0.2V or : UB# ≥ V_{CC} -0.2V, ≤ 0.2V, V_{CC} -0.2V	
		-	4*1	12	μА	~+25°C	Vin ≥ 0V BYTE# ≥ Vcc -0.2V or	
Data retention current	Iccdr	-	7*2	24	μА	~+40°C	BYTE# \leq 0.2V (1) 0V \leq CS2 \leq 0.2V or	
Data retention current		-	-	50	μА	~+70°C	(2) CS1# \geq V _{CC} -0.2V, CS2 \geq V _{CC} -0.2V or (3) LB# = UB# \geq V _{CC} -0.2V,	
		-	-	80	μА	~+85°C	CS1# ≤ 0.2V, CS2 ≥ V _{CC} -0.2V	
Chip select to data retention time	t _{CDR}	0	-	-	ns	See retention waveform.		
Operation recovery time	t _R	5	-	-	ms			

Note 1. Typical parameter indicates the value for the center of distribution at 3.0V (Ta= 25°C), and not 100% tested.

- 2. Typical parameter indicates the value for the center of distribution at 3.0V (Ta= 40°C), and not 100% tested.
- 3. CS2 also controls address buffer, WE# buffer ,CS1# buffer ,OE# buffer ,LB# ,UB# buffer and Din buffer. If CS2 controls data retention mode, Vin levels (address, WE# ,OE#,CS1#,LB#,UB#,I/O) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be CS2 ≥ Vcc-0.2V or0V ≤ CS2 ≤ 0.2V. The other input levels (address, WE# ,OE#,CS1#,LB#,UB#,I/O) can be in the high impedance state.

Low Vcc Data Retention Timing Waveforms*1



Note1. BYTE# ≥ Vcc – 0.2V or BYTE# ≤ 0.2V

Revision History

R1LV3216R Series Data Sheet

		Contents of Revision		
Rev.	Date	Page	Description	
0.01	Mar.24, 2008	-	Initial issue: Preliminary Data Sheet	

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